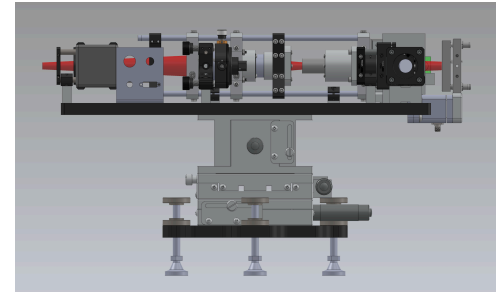


Twyman-Green LUPI Interferometer for System Wavefront Testing

Available with Temporal Phase Shifting Acquisition or
Vibration Insensitive Phase Measurement for Harsh Environments

System Overview

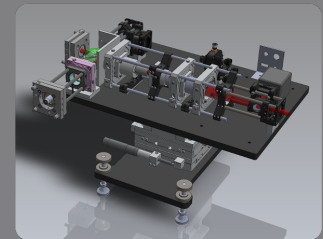
| | |
|---------------------------------|--|
| Output Beam Diameter | 9 mm available |
| Optical Centerline | 108 mm |
| Focus Range | Fixed |
| Interferometer Size (L x W x H) | 41.5 x 54.5 x 10.0 cm |
| Weight | 5.7 kg |
| Measurement Techniques | Mechanical Phase Shifting or Vibration Insensitive Carrier Fringe |
| Alignment System | Threaded, external on-axis visible laser |
| Light Source | 633 & 1550 nm external to interferometer |
| Coherence Length | 20 meter |
| Output Polarization | Linear or Circular |
| Camera Resolution | 1022 x 1022 |
| Shutter Speed (shortest) | 9 μ s |
| Digitization | 8 bit |
| Computer & Software | High-Performance PC, Windows 10 64-bit OS & REVEAL Software |
| Mounting Configurations | Horizontal or Vertical or Adjustable |
| Accessories | 5-Axis mount & Diverger Lenses |



Multiple Configurations

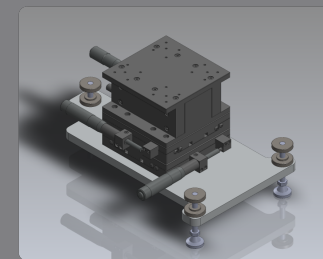
Open Frame

Sometimes you just want every knob to turn. The open frame configuration lets you do just that. Move the camera, adjust the source, change the reference arm... its up to you.



Adjustable 5-Axis Mount:

ÄPRE's fully adjustable 5-Axis mount to make aligning your optics easy



Performance

| | |
|--|--|
| Image Resolution | 25 μ m |
| Image Distortion | <1%, 0.5% typical |
| Fringe Resolution | ~200 fr/aperture |
| Retrace Error ³ @ 200 fringes | < λ /10 |
| RMS Simple Repeatability ¹ | <0.6 nm RMS 1 σ – with NO averaging |
| RMS Wavefront Repeatability ² | <0.6 nm RMS 1 σ – with NO averaging |
| Measurable Part Reflectivity | 0.5% to 100% Specify |

Environment

| | |
|------------------------|--------------------------------------|
| Temperature | 15°C to 30C |
| Δ T/ Δ t | <1.0°C/15 min |
| Humidity | 5 to 95% relative, non-condensing |
| Vibration Isolation | Isolation System recommended for PSI |

¹ RMS Simple Repeatability is defined as 2X the standard deviation of the RMS for 36 sequential measurements (0 averages) of a short plano cavity

² RMS Wavefront Repeatability is defined as the mean RMS difference between a synthetic reference (defined as the average of a 36 sequential measurements) and each measurement plus 2X the standard deviation

³ Retrace Error is defined as the PV residual error between a nulled measurement (the reference), subtracted from a measurement with 500 fringes of tilt, and expressed by the first 36 Zernike polynomials

Traceable Measurement to Report <5 seconds

Traceable Metrology

Saved profiles/process trees and report library assure analysis stability user to user, day to day. Data saved with all raw data, masks and filters...you know today and tomorrow how you got your results.

Easy to Learn, Backward Compatible & 64 bit Stable

Internet browser like design is familiar and uncluttered and easy to learn and with .dat file formats you can save new data compatible with you database or analyze old data on REVEAL. With 64 bit Windows 10 operation large data sets are easily handled and your IT department will appreciate the W10 security.

A Complete Metrology Package - selected parameters

| APPLICATIONS | FILTERS | ANALYSIS | RESULTS |
|--|---|--|--|
| <ul style="list-style-type: none"> ✓ BASIC <ul style="list-style-type: none"> • Form • Radius of Curvature ✓ Fourier¹ <ul style="list-style-type: none"> • MTF • PSF • PSD ✓ Optical Shop Testing¹ <ul style="list-style-type: none"> • Wedge • Polished Homogeneity • Corner Cube | <ul style="list-style-type: none"> ✓ Masking ✓ Auto Aperture ✓ Reference Subtract ✓ Box ✓ Erosion (inside/out) ✓ Median ✓ Individual Zernike ✓ Spike ✓ Affine Transforms | <ul style="list-style-type: none"> ✓ Acquisition Modes <ul style="list-style-type: none"> • Vibration • Tolerant PSI • Wavelength Shifting • Vibration Insensitive ✓ Zernike ✓ 3D View ✓ PVr ✓ Islands ✓ ISO10110-14 ✓ Ogive | <ul style="list-style-type: none"> ✓ ISO & Seidel ✓ PV, RMS ✓ PVr ✓ Tilt ✓ Power (Zernike) ✓ Power (Deviation) ✓ Astigmatism ✓ Coma ✓ SA3 ✓ 1D Profiles ✓ Lengths |

¹Optional Analysis Package

What Users are Saying

"I found the analysis tree to be the most valuable feature of the REVEAL software. It gives the user visibility into the many layers of data processing that occur when making a measurement."

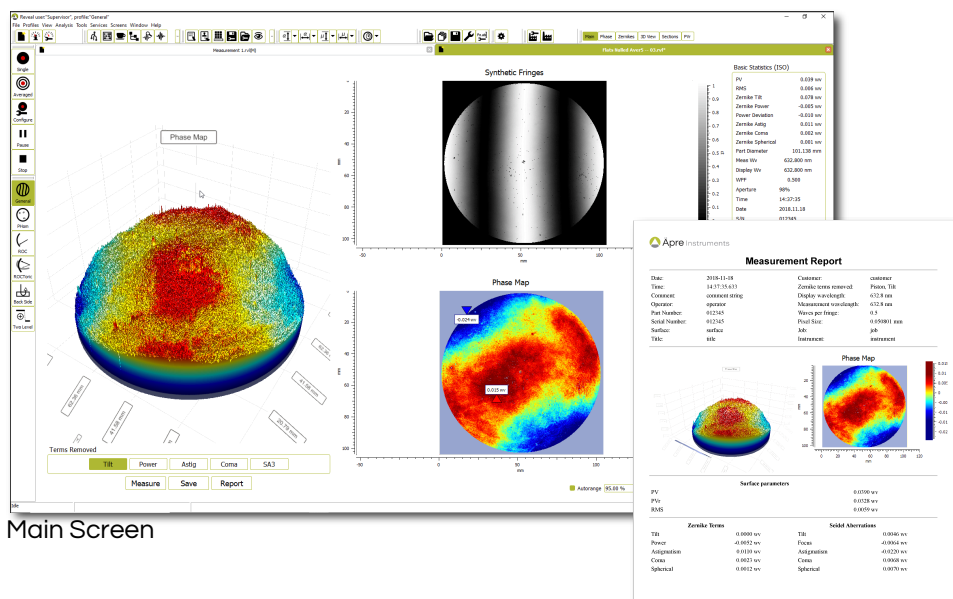
H. Balonek, Optikos

"REVEAL software is intuitive, easy to navigate and very capable in a myriad of applications, but the thing I appreciate most about it is the extensive, exceptionally organized, visually pleasing and effortlessly generated reports."

S. Iles, Edmund Optics

"[REVEAL] has a very user friendly interface and offers multiple ways to view the data. This makes analysis and qualification quick and easy."

A. Godina, Supply Chain Optics"



Main Screen

Example Report

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Instruments™

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